

Status of the Inner-wall Thermal Conducting Film (ITCF) Study

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Outline

- 1. Background: Importance of High Thermal Conductivity
- 2. Idea of Inner-wall Thermal Conducting Film (ITCF) + Simulation
- 3. Nb Thermal Conductivity as Baseline
 - Model and Calculation
 - Nb Sample Test
- 4. Preliminary Result of ITCF
 - Coating Quality
 - Thermal Conductivity Measurement
- 5. Summary and Future Work



Background

RF Dissipation

$$P_{loss} = \frac{1}{2} \int_{S} R_{s} |\mathbf{H}|^{2} \, ds$$

Quality Factor

$$Q = \frac{\omega_0 U}{P_{loss}} = \frac{constant}{R_S} = \frac{\Gamma}{R_S}$$

Surface Resistance R_s derived from P_{loss} : $R_s = A_s \omega^2 \exp(-\frac{\Delta(0)}{k_B T}) = R_0 + R_{BCS}$ $R_{BCS}(T) = \frac{Af^2}{T} e^{-\frac{\Delta}{k_B T}}$





Background



The Necessity of High Thermal Conductivity

T distribution with multiple *B* field



T distribution with multiple B field (From defect to Liquid He) [1].



The Necessity of High Thermal Conductivity



[1], H. Padamsee, HEAT TRANSFER AND MODELS FOR BREAKDOWN, https://epaper.kek.jp/srf80/papers/srf80-7.pdf



RF dissipation on a defect





RF dissipation on a defect





RF dissipation on a defect

Inner-wall Thermal Conducting Film (ITCF), an extra thermal conducting route

 Select low tanδ material: No RF dissipation





RF dissipation on a defect

Inner-wall Thermal Conducting Film (ITCF), an extra thermal conducting route

- Select low tanδ material: No RF dissipation
- ITCF direct contact to heat source, high efficiency
- Can combine any cavity (Nb, Nb₃Sn, MgB₂, SIS)







Material Selection: Thermal Conductivity

200 Highly purified

NaF

2

5

10 20

Temperature, K

50 100

[1]

in W cm⁻¹ K⁻¹

Thermal conductivity,

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- 1. Relatively high κ at 2K 4K (atomic crystal, low κ at low 7)
 - SiC: $\kappa \sim 100$ W/(mK) @ 10K, rule out

 $K (\sim cv\ell) \cdot Low T: K \sim c \sim T^3$

• High *T*: *K* ~ *l* ~ 1/*T*

[1] Boer and Pohl, Semiconductor Physics 2018

[17] Fuschillo, N., B. Lalevic, and N.K. Annamalai, *Dielectric properties of amorp* 145-154.

[20] Morelli, D.T. and G.A. Slack, High Lattice Thermal Conductivity Solids, in High Thermal Conductivity Materials, S.L. Shindé and Goela, Editors. 2006, Springer New York; New York, NY. p. 37-68.

[22] Inc., R.S. Sapphire Optical and Thermal Properties Graph. 2021; Available from: <u>https://rayotek.com/PDF/Sapphire-Optical-and-Thermal-Properties-Graph.pdf</u>.

[41] Microwave101. Alumina 99.5% Encyclopedia. 2023; Available from: <u>https://www.microwaves101.com/encyclopedias/alumina-99-5</u>.
[42] Microwave101. Sapphire Encyclopedia. 2023; Available from: <u>https://www.microwaves101.com/encyclopedias/sapphire</u>.
[43] Microwave101. Aluminum Nitride Encyclopedia. 2023; Available from: <u>https://www.microwaves101.com/encyclopedias/aluminum-</u>





Material Selection: Other Requirement

- 1. Relatively high κ at 2K 4K(atomic crystal, low κ at low 7)
- 2. Dielectric with low loss tangent $tan\delta$
- $Nb_2O_5 \ tan\delta = 0.05 @ 0.2 MHz$ ٠
- 3. Easy to coat to µm level, similar crystal structure with Nb
- 4. SEY?

[2] Ling Huang and Qian Wang 2023 J. Phys.: Conf. Ser. 2433 012002
[17] Fuschillo, N., B. Lalevic, and N.K. Annamalai, Dielectric properties of amorphous Nb2O5 thin
<i>films</i> . Thin Solid Films, 1975. 30 (1): p. 145-154.
[20] Morelli, D.T. and G.A. Slack, High Lattice Thermal Conductivity Solids, in High Thermal
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[43] Microwave101. Aluminum Nitride Encyclopedia. 2023; Available from:
https://www.microwaves101.com/encyclopedias/aluminum-nitride#

Serial No.	Material name	E_1/eV	E_2/eV	$E_{\rm max}$ /eV	$\sigma_{\scriptscriptstyle m max}$
11	Silicon dioxide	<50	>3000	420	4.35
12	White mica	<50	>3000	340	4.33
13	Silicon nitride	75	>3000	680	2.43
14	Boron nitride	75	>3000	450	2.68
15	Carborundum	<50	3000	360	2.93
16	Zirconium oxide	<50	>3000	380	3.35
17	Aluminium nitride	<50	>3000	420	3.08
18	Aluminium oxide	<50	>3000	630	4.55
19	Magnesium oxide	<50	>3000	430	3.26
20	Ferrite	<50	>3000	320	2.38

Table 2. Measurement results of SEY values for different dielectric materials. [2]

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COMSOL Simulation Results



Thermal Conductivity of Nb (Baseline)

Model
SRF cavity operation ~
$$B_{c1}$$
, only considering electron and phonon transfer heat
 κ for NC: $\kappa_n(T, RRR, l) = \left[\frac{1}{A RRR T} + aT^2\right]^{-1} + \left[\frac{1}{DT^2} + \frac{1}{BlT^3}\right]^{-1}$
 κ for SC: $\kappa_s(T, RRR, l) = R(y) \left[\frac{1}{A RRR T} + aT^2\right]^{-1} + \left[\frac{1}{DT^2 e^y} + \frac{1}{BlT^3}\right]^{-1}$
Energy Gap/ k_BT : $y = \frac{\Delta(T)}{k_BT} \approx \frac{\Delta(0)}{k_BT} \left[\cos\left(\frac{\pi T^2}{2T_c^2}\right)\right]^{\frac{1}{2}}$
Ratio of SC electrons
over NC electrons: $R(y) = \frac{12}{\pi^2} \left[f(y) + y \ln(1 + e^{-y}) + \frac{y^2/2}{1 + e^y}\right]$, $f(y) = \int_0^\infty \frac{zdz}{1 + e^{z+y}}$
 $A = 0.141$ W K⁻² m⁻¹, $a = 7.52 \times 10^{-7}$ W⁻¹ K⁻¹ m, $B = 4.34 \times 10^3$ W K⁻⁴ m⁻², $1/D = 2.34 \times 10^2$ W⁻¹K³m [1]

[1] F.Koechlin, and B.Bonin, PARAMETRISATION OF THE NIOBIUM THERMAL CONDUCTIVITY IN THE SUPERCONDUCTING STATE, SRF1995 Gif-sur-Yvette, France, srf95f24



Thermal Conductivity of Nb (Baseline)

Introducing $T_c(B)$ to the equation

Below B_{c2} , the influence of B on κ of a superconductor (simplified for static magnetic fields) primarily arises from breaking Cooper pairs, leading to changes in the energy gap or, alternatively, manifesting as changes in T_c :

$$B_{c2} = B_{c2,T=0} \left[1 - \left(\frac{T_c}{T_{c,B=0}} \right)^2 \right]$$
$$T_c(B) = T_{c,B=0} \times \sqrt{1 - \frac{B}{B_{c2}}}$$

• Add an extra parameter to manipulate κ and get an extra equation

By substituting the expression for $T_c(B)$ into y, and then substituting y into κ_s , use Python code to calculate the κ for high-purity (RRR=200 is chosen for calculation) and low-purity (RRR=85 is chosen for this calculation, corresponding to the test value of the sample used in subsequent experiments) materials.



Calculated κ vs *B* for Nb (using Python)

- 1. Large-grain low-*RRR* $\kappa(B)$ shows valley on the curve
- 2. (Relatively) Small grain $\kappa(B)$ curve no valley
- 3. @4K, the influence of grain size on the $\kappa(B)$ curve is low



Thermal conductivity vs B/B_{c2} for multiple parameters.



Explanation of the "Valley" on the $\kappa(B)$ curve for some parameters



RRR = 85, l = 0.5 mm, the increase in T @ B = 0 mT and the increase in B @ T = 2 K both change κ and the y-value (right vertical axis).

- 1. At low T & B, κ_l (for lattice) dominates. T or B increase breaks Cooper pairs, κ_e increase and gradually dominants κ
- 2. As the *T* rises, increasing $n_{e,nc}$ enhances phonon scattering, adding a decrease κ_l (instead of monotonically increasing with *T*) when the decreasing is obvious (in some range of RRR and grain size) => phonon peak
- 3. As the *B* rises, the growing $n_{e,nc}$ enhances phonon scattering, leading to a decrease in κ_l and an increase in $\kappa_e \Rightarrow$ "valley"



Testing System

Cryogen-free magnets Property Measurement System (CPMS) [1]



Sample Stick

Thermal test sample holder & sample

[1] CSSC Pride, https://www.724pridecryogenics.com/en/



Sample Test of Nb

Sample test, Electrical

To validate our computational findings, we conducted electrical and thermal transport measurements on a low-purity niobium sample with dimensions of 10*1*1 mm (supplier-provided RRR=40, grain size approximately 0.01 mm).





Sample Test of Nb

Sample test, Thermal





Sample Test of Nb



- 1. At temperatures of 2 K, 4 K, and 6 K, valley observed in thermal conductivity within the low magnetic field range, while thermal conductivity remains constant at higher magnetic fields (up to 700 mT for 2K test).
- 2. The overall κ values are higher than calculated, with values around 50 W/(mK) at 2 K.
- 3. Test results indicate that below B_c , fluctuations in κ are more pronounced, reaching over 30%, vortex contribution, grain shape (long and narrow), defect?



Preliminary Results of Thermal Conducting Film



Coating Quality

BCP + ALD **20 nm Al₂O₃** Optical Microscope (50x, 200x, 1000x)

- 1. We did not make perfect substrate before coating (rough surface)
- 2. After ALD, no much changes on the surface morphology, similar to Nb surface
- 3. After 1 µm AIN DCMS, no cracking, see bubbles or clusters?



BCP + ALD **20 nm Al₂O₃** + Magnetic Sputtering **1 μm AIN** Optical Microscope (50x, 200x, 1000x)





BCP + ALD 20 nm Al₂O₃ Scan Electron Microscope (SEM)



BCP + ALD 20 nm Al₂O₃ + Magnetic Sputtering 1 μm AIN Scan Electron Microscope (SEM)

Thermal Conductivity of the Coated Sample





Thermal Conductivity of the Coated Sample

Ongoing/Future Work

1. Statistic test results of $\kappa_{sample}(7)$

2. Error analysis: size variation, ITCF on the side

3. Separate the κ_{Nb} and κ_{film} , by adding *B* field, each *B* get an extra equation with two unknowns

4. Upgrade thermal test module with laser heating (more like RF heating on the metal surface instead of on the side), considering material absorption

5. Optimizing film quality (annealing, change MS parameters, cleaning…)





Summary

- 1. Review of ITCF Concept and Film Selection
- 2. Calculation and Testing of Thermal Conductivity in Nb Samples
 - Utilizing Python, serving as a baseline for subsequent sample testing.
 - Valley on the $\kappa(B)$ curve
- 3. Preliminary ALD+MS Coating Samples
 - no cracking, clusters exist
 - thermal conductivity deviates from the Nb baseline: higher κ @ 3-5K
- 4. Ongoing Work:
 - Error analyzing, test system upgrading, and coating process optimizing.



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